


<b>Search Notes</b>  	<b>Application/Control No.</b>  10582513	<b>Applicant(s)/Patent Under Reexamination</b>  YAMAGISHI ET AL.
	<b>Examiner</b>  Eoff, Anca	<b>Art Unit</b>  1722

SEARCHED			
Class	Subclass	Date	Examiner
430	270.1, 326	10/26/2011	AE
523	332, 340	10/26/2011	AE
528	480, 491, 493, 494, 496	10/26/2011	AE

SEARCH NOTES		
Search Notes	Date	Examiner
Updated search in EAST	10/26/2011	AE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
430	270.1, 326	10/26/2011	AE
523	332, 340	10/26/2011	AE
528	480, 491, 493, 494, 496	10/26/2011	AE

	/A.E./ Primary Examiner.Art Unit 1722
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